

RESULT LIST

Approximately **50** results found in the Worldwide database for:

pattern match in the title

(Results are sorted by date of upload in database)

- 1 Matrix pattern match techniques for uninstalling multiple dependent components**
Inventor: CHEN PAUL M (CA); VYTAS PAUL D (CA) Applicant: IBM (US)
EC: IPC: (IPC1-7): G06F9/44
Publication info: **US2005289513** - 2005-12-29
 - 2 Match circuit for performing pattern recognition in a performance counter**
Inventor: ADKISSON RICHARD W (US) Applicant:
EC: IPC: (IPC1-7): G06F15/00; G01R31/28; G06F15/76
Publication info: **US2005273682** - 2005-12-08
 - 3 Pattern match member**
Inventor: QIU ZEYOU (CN) Applicant: QIU ZEYOU (CN)
EC: IPC: **E04B5/36; E04B5/32**; (IPC1-7): E04B5/36
Publication info: **CN1566578** - 2005-01-19
 - 4 Pattern match member**
Inventor: QIU ZEYOU (CN) Applicant: QIU ZEYOU (CN)
EC: IPC: **E04B5/36; E04B5/32**; (IPC1-7): E04B5/36
Publication info: **CN1566564** - 2005-01-19
 - 5 MEMORY SYSTEM**
Inventor: VAN BROCKLIN ANDREW L (US); SMITH KENNETH (US); (+2) Applicant:
EC: G11C11/15 IPC: **G11C11/15; G11C11/02**; (IPC1-7): G11C11/15
Publication info: **US2004246774** - 2004-12-09
 - 6 Storage-device and address decoding method and apparatus thereof conducted in bit-pattern match**
Inventor: CAI RIXING (CN) Applicant: WEISHENG ELECT CO LTD (CN)
EC: IPC: **G06F7/38; G06F12/06; G06F7/38** (+3)
Publication info: **CN1438577** - 2003-08-27
 - 7 Method and apparatus for performing fast closest match in pattern recognition**
Inventor: KRAVEC KERRY A (US); SAIDI ALI G (US); (+2) Applicant: IBM (US)
EC: G06K9/00Y IPC: **G06K9/00; G06K9/00**; (IPC1-7): G06K9/68
Publication info: **US2004184662** - 2004-09-23
 - 8 METHOD AND SYSTEM FOR PERFORMING A PATTERN MATCH SEARCH FOR TEXT STRINGS**
Inventor: BASSO CLAUDE; CALVIGNAC JEAN LOUIS; (+4) Applicant: IBM (US); IBM UK (GB)
EC: G06F17/30P2 IPC: **G06F17/30; G06F17/30**; (IPC1-7): G06K9/00
Publication info: **WO03005288** - 2003-01-16
 - 9 Method and apparatus for pattern match filtering for real time acoustic pipeline leak detection and location**
Inventor: YANG BAO-WEN (US); RECANE MARION (US) Applicant:
EC: G01M3/24B IPC: **G01M3/24; G01M3/24**; (IPC1-7): G01M3/08
Publication info: **US2002124633** - 2002-09-12
 - 10 Transistor nanostructure ion beam adjustment process having test shaped formed using digital reference pattern, then original image compared and adjustment made/process continued until good match obtained**
Inventor: Applicant: CENTRE NAT RECH SCIENT (FR)
EC: H01J37/304; H01J37/305B2 IPC: **H01J37/304; H01J37/305; H01J37/30** (+3)
Publication info: **FR2823008** - 2002-10-04
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RESULT LIST

0 results found in the Worldwide database for:

Indexing technique pattern match in the title

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Data supplied from the **esp@cenet** database - Worldwide